

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. <b>03560.003310</b>		APPLICATION NO. <b>10/601,777</b>	
APPLICANT <b>Tadashi Okamoto et al.</b>				FILING DATE <b>June 24, 2003</b>		GROUP <b>1631</b>	

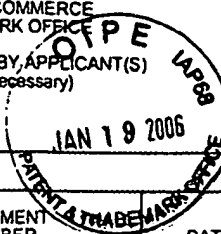
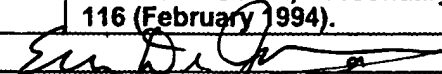
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
EDJ		5,633,495	05/27/97	Neihuis et al.	250	287	

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
EDJ	JP	60-49252	03/18/85	Japan			Abstract
↓	JP	9-500486	01/14/97	Japan			Translation
↓	JP	7-151836	06/16/95	Japan			Translation

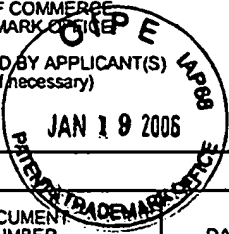
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

EXAMINER	DATE CONSIDERED <b>02/17/2006</b>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
EDJ		5,589,685	12/31/96	Jen Wu et al.	250	282	
		6,002,128	12/14/99	Hill et al.	250	287	
		2001/0055813 A1	12/27/01	Winograd et al.	436	89	
		5,821,060	10/13/98	Arlinghaus et al.	435	6	
		2002/0074517 A1	06/20/02	Krutchinsky et al.	250	492.1	
		4,983,831	01/08/91	Migeon et al.	250	309	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
EDJ	DE	31 44 604 A1	05/19/83	Germany			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EDJ		Steven M. Hues et al., "A Pulsed Alkali-Ion Gun for Time-of-Flight Secondary Ion Mass Spectrometry," 60(7) Rev. Sci. Instrum. 1239-44 (July 1989).					
		Viswanatham Katta et al., "A Pulsed Ion Bombardment Time-of-Flight Mass Spectrometer with High Sensitivity for the Analysis of Peptides," 105 Int. J. Mass Spectrom. Ion Processes 129-45 (1991).					
		J. Schwieters et al., "High Mass Resolution Surface Imaging with Time-of-Flight Secondary Ion Mass Spectroscopy Scanning Microprobe," 9(6) J. Vac. Sci. Technol. 2864-71 (1991).					
		Robert W. Odom, "Secondary Ion Mass Spectrometry Imaging," 29(1) Appl. Spectros. Rev. 67-116 (February 1994).					
EXAMINER				DATE CONSIDERED			
				<b>02/17/2005</b>			

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<div style="text-align: center;">  </div>		APPLICANT <b>Tadashi Okamoto et al.</b>			
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
	<b>G.C. Rider et al., "Imaging Time-of-Flight SIMS - A New Technique for Spatially-Resolved Chemical Surface Analysis," 4(1) J. Molecul. Electron. 402 (1988) (Abstract).</b>
	<b>Anthony J. Nicola et al., "Enhancement of Ion Intensity in Time-of-Flight Secondary-Ionization Mass Spectrometry," 7 J. Am. Soc. Mass Spectrom. 467-71 (1996).</b>

EXAMINER <i>E. De Jong</i>	DATE CONSIDERED <b>02/17/2006</b>
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